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PATENT & TRADEMARK OFFICE

FORM PTO-1449 (REV. 7-80)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. NIT-163-02	SERIAL NO. 10/075,283
	LIST OF DOCUMENTS CITED BY APPLICANT *(Use several sheets if necessary)*	APPLICANT M. IWAYAMA et al	
		FILING DATE February 15, 2002	GROUP 2142 165

U.S. PATENT DOCUMENTS

* EXAMINER INITIAL		DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If Appropriate)
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
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	AK						

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES	TRANSLATION NO
NAo	AL	9-218881	08/1997	JAPAN			☒	☐
hMy	AM	4-138563	05/1992	JAPAN			☒	☐
	AN						☐	☐

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

MMy	AR	"Dynamic Co-occurrence Analysis for Interactive Document Retrieval", by Yoshiki Niwa, Advanced Research Laboratory, Hitachi, Ltd., pgs. 41-48 (including English-Language Translated Abstract). N) Date
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	7/25/05

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LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary)				FILING DATE February 15, 2002		GROUP 2175 2165	

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NAJ	AA	5,590,319	12/31/96	Cohen et al			
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		DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES	TRANSLATION NO
NAJ	AL	64-74210	03/20/89	Japan			☐	☐
NAJ	AM	93/37499	08/27/98	WO PCT			☐	☐
NAJ	AN	10-74210	03/17/98	Japanese Laid-Open Patent			☐	☐
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EXAMINER INITIAL		DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES	NO
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	AN						☐	☐
	AO						☐	☐
	AP						☐	☐

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